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Advances in Radar Technology for Remote Sensing

Guest Editors:

Dr. Lapo Miccinesi

Department of Information Engineering, University of Florence, Via Santa Marta 3, 50139 Firenze, Italy

Prof. Dr. Massimiliano Pieraccini

Department of Information Engineering, University of Florence, Via Santa Marta 3, 50139 Firenze, Italy

Deadline for manuscript submissions:

closed (20 June 2023)

Message from the Guest Editors

This Special Issue intends to present scholarly papers that address advances in radar technology for remote sensing purposes, and aims to collect and present advances in the following topics:

- Radar techniques for remote sensing;
- Ground-based synthetic aperture radar (SAR);
- Interferometric radar:
- Multiple-input multiple-output radar;
- Unmanned aerial system-borne radar;
- High-frequency radar;
- Three-dimensional imaging radar;
- Ground-penetrating radar;
- Space-borne SAR;
- Aerial-borne SAR.

You are invited to submit your high-quality manuscripts for publication in this Special Issue.











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Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

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